Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/050,123	YEN ET AL.	
Examiner	Art Unit	
Jason M. Perilla	2638	

	SEAR	CHED	
Class	Subclass	Date	Examiner
375	295	9/29/2005	JP
	146	9/29/2005	JP
	296	9/29/2005	JP
	297	9/29/2005	JP
710	8	9/29/2005	JP

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East USPAT/USPGPUB EPO/JPO	9/29/2005	JP	
Inventor Name Search	9/29/2005	JP	
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